TOSHIBA TA1230Z

TOSHIBA BIPOLAR LINEAR INTEGRATED CIRCUIT SILICON MONOLITHIC

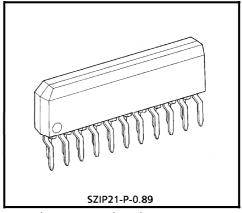
TA1230Z

TV SOUND MULTIPLEX BROADCAST DEMODULATOR IC FOR EIAJ SYSTEM

The TA1230Z incorporates the functions required for EIAJ system TV sound multiplex broadcast demodulation and a trap for eliminating facsimile broadcast signals multiplexed in the sound multiplex broadcasting band. Automatic adjustment based on a 32 f_H-oscillator makes adjustments other than separation unnecessary.

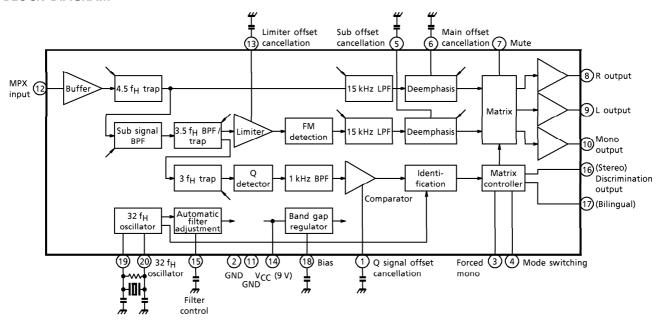
FEATURES

- Self-adjusting filter and discriminator circuit based on a 32 f_H-oscillator
- Built-in trap eliminates facsimile broadcast signals



Weight: 1.00 g (Typ.)

BLOCK DIAGRAM



980910EBA1

- TOSHIBA is continually working to improve the quality and the reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to observe standards of safety, and to avoid situations in which a malfunction or failure of a TOSHIBA product could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent products specifications. Also, please keep in mind the precautions and conditions set forth in the TOSHIBA Semiconductor Reliability Handbook.
- The products described in this document are subject to the foreign exchange and foreign trade laws.

 The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any intellectual property or other rights of TOSHIBA CORPORATION or others.

The information contained herein is subject to change without notice.

PIN FUNCTIONS

PIN No.	PIN NAME	FUNCTION	INTERFACE CIRCUIT
1	Q signal offset cancellation	Cuts the DC component of the circuit shaping the waveform of the AM-detected cue signal. Connect a 0.1 μ F capacitor between this pin and GND. A 0.01 μ F capacitor may cause lower discrimination sensitivity because of the fluctuations in a capacitor of that rating.	10 10 47 KD
2	GND	_	_
3	Forced mono	Setting this pin to 5 V forcibly sets the mode to mono. This does not affect the discrimination output or bilingual broadcast decoding. As this is the PNP transistor input circuit, leaving the pin open sets the mode to forced mono. However, do not leave the pin open.	14 1 1 2.5 V
4	Mode switching	The voltage of this pin is used to control the output state for bilingual broadcasting. 0 V : Main sound 2.5 V : Main/sub sound 5 V : Sub sound 9 V : Main/sub sound	(4) (1) (1) (1) (1) (1) (1) (1) (1) (1) (1
5	Sub offset elimination	Cuts the DC component of the sub sound signal processing section. Connect a 10 $\mu \rm F$ capacitor between this pin and GND.	
6	Main offset elimination	Cuts the DC component of the mainsound signal processing section. Connect a 10 μ F capacitor between this pin and GND.	(1) kΩ

PIN No.	PIN NAME	FUNCTION	INTERFACE CIRCUIT
7	Mute	Setting this pin to 5V mutes all the outputs. Normally, fix to GND.	14 2 15 kΩ 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2
8 9 10	R output L output Mono output	Output pins. A mono sound signal is output from pin 10 regardless of the state of pins 3 and 4 and the broadcasting mode. Set so that the maximum current output from these pins does not exceed 500 μ A.	100 CO VIII VIII VIII VIII VIII VIII VIII V
11	GND	_	_
12	MPX input	Sound multiplex signal input pin. The input resistance is $10k\Omega$ (Typ.). The standard input level is $250\text{mV}_{\text{rms}}$ (Equivalent to 100% modulation)	
13	Limiter offset elimination	Cuts the DC component of the sub-sound signal demodulation section. Connect a 0.01 $\mu {\rm F}$ capacitor between this pin and GND.	9.5 kΩ
14	vcc	The operating power supply voltage range is 9 V ± 10%.	_
15	Filter control	Used for the automatic filter adjustment circuit incorporated into the IC. Connect a 0.01 $\mu \rm F$ capacitor between this pin and GND.	(5) (1) (2) (1) (1) (1) (1) (1) (1) (1) (1) (1) (1
16 17	Stereo discrimination output Bilingual discrimination output	Broadcast mode discrimination output pins. This circuit is an open collector whose maximum sink current is 1 mA.	16 100 Ω 17 100 Ω

PIN No.	PIN NAME	FUNCTION	INTERFACE CIRCUIT
18	Bias	Eliminates IC internal bias noise. Connect a 10 $\mu {\rm F}$ capacitor between this pin and GND.	(1) (1) (1) (1) (1) (1) (1) (1) (1) (1)
19 20	32 f _H oscillation	Ceramic oscillator connecting pins. TA1230Z uses this oscillation to automatically adjust the internal filter and to perform discrimination. Use a Murata CSB503E7 ceramic oscillator.	(a) 100 Cl (b) 100 Cl (c) 100 Cl

TOSHIBA TA1230Z

ABSOLUTE RATINGS (Ta = 25° C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	Vcc	15	V
Power Dissipation	PD	890	mW
Operating Temperature	T _{opr}	− 20~75	°C
Storage Temperature	T _{str}	- 55∼150	°C

(Note) The power dissipation rating drops by 7.2 mW for every 1°C over 25°C.

RECOMMENDED SUPPLY VOLTAGE

PIN No.	PIN NAME	MIN.	TYP.	MAX.	UNIT
14	Vcc	8.1	9.0	9.9	V

ELECTRICAL CHARACTERISTICS (Unless otherwise specified, V_{CC} = 9 V, Ta = 25°C) DC CHARACTERISTICS

CHARACTERISTIC	SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Current Dissipation	lcc	_	_	28	34	42	mΑ
	V ₁	_	_	4.2	5.2	6.2	
	V ₅	_	_	3.5	4.5	5.5	
	V ₆	_		3.5	4.5	5.5	
	V ₈	_	_	2.1	3.1	4.1	
	V ₉	_	_	2.1	3.1	4.1	
Din Valtage	V ₁₀		_	2.1	3.1	4.1	.,
Pin Voltage	V ₁₂	_	_	3.5	4.5	5.5	V
	V ₁₃	_	_	2.8	3.9	4.9	
	V ₁₅	_	_	2.5	4.5	6.5	
	V ₁₈	_	-	5.0	5.7	6.4	
	V ₁₉	_	_	3.5	4.5	5.5	
	V ₂₀		_	7.0	7.6	8.2	

AC CHARACTERISTICS

AC CHARACTERISTICS									
CHAF	RACTERISTIC	SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Output Level		Vout	_	(Note 1)	500	600	700	mV _{rms}	
Output Level Flu	ctuation	∆Vout	_	(Note 2)	_	0.0	1.5	dB	
Sub Output Leve	l Power Dependency	∆VSUB	_	(Note 3)	_	0.0	0.5	dB	
	Main Sound 100 Hz	A100 M	_		0.0	1.0	2.5		
Frequency	Main Sound 10 kHz	A10k M	_	(Note 4)	- 16	- 13	- 10	-ID	
Characteristics	Sub Sound 100 Hz	A100 S	_	(Note 4)	0.0	1.0	2.5	dB	
	Sub Sound 10 kHz	A10k S	_		- 16	- 13	- 10		
Total Harmonic	Main Sound	THD M	_	(Note 5)	_	0.2	1.0	- %	
Distortion	Sub Sound	THD \$	_	(Note 5)	_	0.7	1.0	%	
S/N	Main Sound	S/N M		(Note 6)	70	75	_	4p	
3 / IN	Sub Sound	S/N S	_	(Note 6)	60	65	_	dB	
Carrier Leakers	Main Sound	VLeak M	_	(Note 7)	_	50	70	mV _{p-p}	
Carrier Leakage	Sub Sound	VLeak S	_	(Note /)	_	50	70		
Stereo Separation	n e	Sepa	_	(Note 8)	34	_	_	dB	
Bilingual Crosstal	k	СТ	_	(Note 9)	60		_	dB	
	Main (Max.)	Vmax M	_	(Note 10)	1.0		_	- V	
Dilingual Mada	Main/Sub (1) (Min.)	Vmin B (1)	_			_	1.2		
Bilingual Mode Switching	Main/Sub (1) (Max.)	Vmax B (1)	_		2.9				
Voltage	Sub (Min.)	Vmin S	_				4.2		
Voltage	Sub (Max.)	Vmax S	_		5.4				
	Main/Sub (2) (Min.)	Vmin B (2)	_				6.6		
Forced Mono	Off Voltage	Vmin FMono	_	(Note 11)	2.4	_		V	
Voltage	On Voltage	Vmax FMono	_	(NOCE II)			2.6	_ '	
Mute on Voltage		V Mute	_	(Note 12)	_	_	2.0	V	
Mute Residual No	oise	V Mute	_	(Note 13)	_	_	1.5	mV _{p-p}	
Mute DC	L/R Output	Vos	_	(Note 14)	_	5	100	mV	
Offset Voltage	M Output		_	(140 (2 14)			300	1110	
Sub Carrier Sensi		S _{SUB}	_	(Note 15)	_		12	dB	
Cue Signal	No Modulation	SQo	_		8		_		
Sensitivity	L-R 900 Hz 100%	SQ900	_	(Note 16)	6		_	dB	
3ensitivity	Sub Sound 1kHz 100%	SQ1k	_		6		_		
Input Resistance		R _{IN}	_	(Note 17)	7	10	13	kΩ	
Output Resistance	e	ROUT	_	(Note 18)	70	100	130	Ω	

TEST CONDITIONS

NOTE	INPUT	MC	DE SETTI	NG	TECT DIN	TEST METUOD
NOTE	SIGNAL	PIN 3	PIN 4	PIN 7	TEST PIN	TEST METHOD
1	Signal A	0 [V]	0 [V]	0 [V]	Pins 8, 9, 10	Measure the output level of each pin (V _{OUT} [mV _{rms}])
2	Signal A	0 [V]	0 [V]	0 [V]	Pins 8, 9	Calculate the output level ratio between pins 8 and 9 (V ₈ , V ₉). Δ VOUT [dB] = 20· $ \ell$ og (V ₈ /V ₉) $ $
3	Signal B	0 [V]	5 [V]	0 [V]	Pins 8, 9	Raise V_{CC} from 8.1V to 9.9 V and measure the output level (V_V') . Calculate the ratio against the output level (V_V) when $V_{CC} = 9V$. $\Delta V_{CC} = 20 \cdot \ell_{CC} $
4	Signal A Signal B Signal C Signal D	0 [V]	0/5 [V]	0 [V]	Pins 8, 9	Set pin 4 to 0 V. Input signal A and measure the output level (V_{M1k}). Next, input signal C, D and measure its output level at 100 Hz and 10 kHz (V_{M100} and V_{M10k}). A100 M [dB] = 20 ℓ og (V_{M100}/V_{M1k}) A10k M [dB] = 20 ℓ og (V_{M10k}/V_{M1k}) Set pin 4 to 5 V. Input signal B and measure the output level (V_{S1k}). Next, input signal C, D and measure its output level at 100 Hz and 10 kHz (V_{S100} and V_{S10k}). A100 S [dB] = 20 ℓ og (V_{S100}/V_{S1k}) A10k S [dB] = 20 ℓ og (V_{S10k}/V_{S1k})
5	Signal A Signal B	0 [V]	0/5 [V]	0 [V]	Pins 8, 9	Set pin 4 to 0 V. Input signal A and measure the distortion factor (THD M [%]). Set pin 4 to 5 V. Input signal B and measure the distortion factor (THD S [%]).
6	Signal A Signal B Signal E	0 [V]	0/5 [V]	0 [V]	Pins 8, 9	Set pin 4 to 0 V. Input signal B and measure the output level (S _M). Next, measure its output level (N _M) on no signal input condition. S/N M [dB] = 20 log (S _M /N _M) Set pin 4 to 5 V. Input signal B and measure the output level (S _S). Next, input signal E and measure its output level (N _S). S/N M [dB] = 20 log (S _S /N _S)
7	Signal E	0 [V]	0/5 [V]	0 [V]	Pins 8, 9	Set pin 4 to 0 V and set LPF output to through. Measure the output level (VLeak M). Set pin 4 to 5 V and set LPF output to through. Measure the output level (VLeak S).

NOTE	INPUT	MC	DE SETTI	NG	TECT DIN	TEST METHOD
NOTE	SIGNAL	PIN 3	PIN 4	PIN 7	TEST PIN	TEST METHOD
8	Signal F	0 [V]	0 [V]	0 [V]	Pins 8, 9	Adjust the input signal amplitude so that the output level of pin 8 is at minimum. Measure the output levels of 1 kHz spectrum of pin 8 (Vg) and pin 9 (Vg) by a spectrum analyzer. Sepa [dB] = 20 log (Vg/Vg)
9	Signal H	0 [V]	2.5 [V]	0 [V]	Pins 8, 9	Measure the output levels of 1 kHz spectrum of pin 8 (V ₈) and pin 9 (V ₉) by a spectrum analyzer. CT [dB] = $20 \log (V_9/V_8)$
10	Signal I	0 [V]	Variable	0 [V]	Pin 4	Raise the voltage of pin 4 from 0 V. Measure the upper limit voltage (Vmax M [V]) holding the output from pin 8 at 1 kHz. Reduce the voltage of pin 4 from 2.5 V. Measure the lower limit voltage (Vmin B (1) [V]) holding the output from pin 8 at 400 Hz. Raise the voltage of pin 4 from 2.5 V. Measure the upper limit voltage (Vmax B (1) [V]) holding the output from pin 9 at 1 kHz. Reduce the voltage of pin 4 from 5 V. Measure the lower limit voltage (Vmin B (1) [V]) holding the output from pin 9 at 400 Hz. Raise the voltage of pin 4 from 5 V. Measure the upper limit voltage (Vmax S [V]) holding the output from pin 9 at 400 Hz. Reduce the voltage of pin 4 from 9 V. Measure the lower limit voltage (Vmin B (2) [V]) holding the output from pin 9 at 1 kHz.
11	Signal E	Variable	0 [V]	0 [V]	Pin 3	Raise the voltage of pin 3 from 0 V. Measure the upper limit voltage (Vmax FMono [V]) holding the output from pin 8 to 0 V. Reduce the voltage of pin 3 from 5 V. Measure the lower limit voltage (Vmin FMono [V]) holding the output from pin 8 at 1 kHz.
12	Signal A	0 [V]	0 [V]	Variable	Pin 7	Raise the voltage of pin 7 from 0 V. Measure the voltage (Vmute [V]) when the output from pin 8 or pin 9 changes to 0 V.
13	Signal A	0 [V]	0 [V]	5 [V]	Pins 8, 9, 10	Measure the output levels of the pins (VMute [mV _{p-p}]).
14	No signal	0 [V]	0 [V]	0/5 [V]	Pins 8, 9, 10	Switch the pin 7 voltage between 0 V and 5 V. Measure the DC voltage change of the pins (VOS [V]).

TEST CONDITIONS

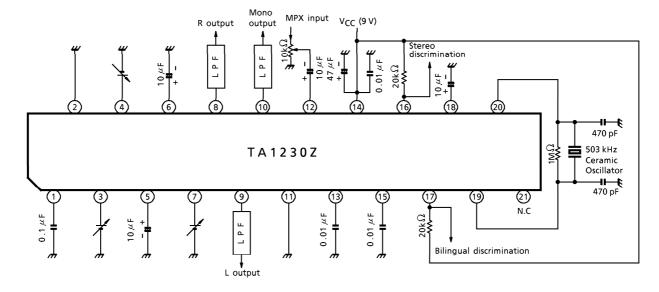
NOTE	INPUT	MC	DE SETTI	NG	TEST PIN	TEST METHOD
NOTE	SIGNAL	PIN 3	PIN 4	PIN 7	I EST PIN	TEST WIETHOD
15	Signal J	0 [V]	0 [V]	0 [V]	Pin 17	Input signal J. Lower the 31.47 [kHz] signal level from 150 [mV _{rms}]. Measure the 31.47 [kHz] signal level when the pin 17 voltage changes to 9 [V] (VSUB). S SUB = 20 log (150 / VSUB) [dB]
16	Signal K Signal L Signal M	0 [V]	0 [V]	0 [V]	Pins 16, 17	Input signal K. Lower the cue signal level from 20 mV _{rms} . Measure the cue signal level when the pin 17 voltage changes to 9 V (V Qo [mV _{rms}]) S Qo [dB] = $20 \log (20 / \text{VQo})$ Input signal L. Lower the cue signal level from $20 \text{mV}_{\text{rms}}$. Measure the cue signal level when the pin 17 voltage changes to 9 V (VQ900 [mV _{rms}]) S Q900 [dB] = $20 \log (20 / \text{VQ900})$. Input signal M. Lower the cue signal level from $20 \text{ [mV}_{\text{rms}}$]. Measure the cue signal level when the pin 16 voltage changes to 9 V (VQ1k [mV _{rms}]) S Q1k [dB] = $20 \log (20 / \text{VQ1k})$.
17	Signal A	0 [V]	0 [V]	0 [V]	Pin 12	Measure the input resistance.
18	Signal A	0 [V]	0 [V]	0 [V]	Pins 8, 9, 10	Measure the output resistance.

INPUT SIGNAL TABLE

SIGNAL	MAIN SIGNAL	SUB S	IGNAL	CUE SIGNAL		
SIGNAL	MAIN SIGNAL	CARRIER	MODULATION	CARRIER	MODULATION	
Signal A	1 kHz, 250 mVrms	No signal	_	No signal	_	
Signal B	No signal	31.47 kHz, 150 mVrms	1 kHz, 100% FM	55.07 kHz, 20 mVrms	922.5 Hz, 60%AM	
Signal C	100Hz, 250 mVrms	31.47 kHz, 150 mVrms	100Hz, 100% FM	55.07 kHz, 20 mVrms	922.5 Hz, 60% AM	
Signal D	10 kHz, 250 mVrms	31.47 kHz, 150 mVrms	10 kHz, 100% FM	55.07 kHz, 20 mVrms	922.5 Hz, 60%AM	
Signal E	No signal	31.47 kHz, 150 mVrms	No signal	55.07 kHz, 20 mVrms	922.5 Hz, 60%AM	
Signal F	1 kHz, 125 mVrms	31.47 kHz, 200 mVrms	1 kHz (In-phase), 50% FM	55.07 kHz, 20 mVrms	982.5 Hz, 60%AM	
Signal G	1 kHz, 250 mVrms	31.47 kHz, 150 mVrms	No signal	55.07 kHz, 20 mVrms	922.5 Hz, 60% AM	
Signal H	1 kHz, 250 mVrms	31.47 kHz, 150 mVrms	1 kHz, 100% FM	55.07 kHz, 20 mVrms	922.5 Hz, 60% AM	
Signal I	1 kHz, 250 mVrms	31.47 kHz, 150 mVrms	400Hz, 100% FM	55.07 kHz, 20 mVrms	922.5 Hz, 60% AM	
Signal J	No signal	31.47 kHz, Variable	No signal	55.07 kHz, 20 mVrms	922.5 Hz, 60%AM	
Signal K	No signal	31.47 kHz, 150 mVrms	No signal	55.07 kHz, Variable	922.5 Hz, 60%AM	
Signal L	No signal	31.47 kHz, 200 mVrms	900Hz, 100% FM	55.07 kHz, Variable	982.5 Hz, 60%AM	
Signal M	No signal	31.47 kHz, 150 mVrms	1 kHz, 100% FM	55.07 kHz, Variable	922.5 Hz, 60%AM	

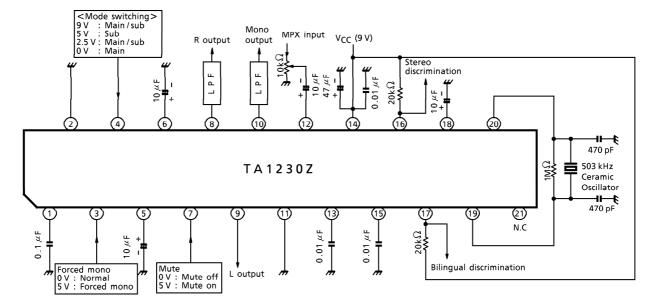
TOSHIBA TA1230Z

TEST CIRCUIT



LFP: 4-stage Butterworth, cutoff frequency 15 kHz

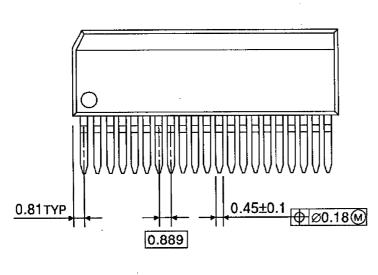
APPLICATION CIRCUIT

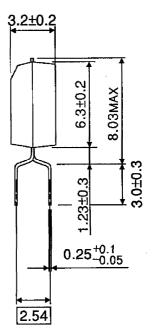


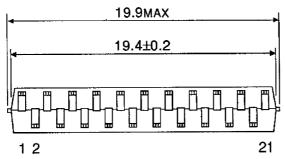
Ceramic oscillator: CSB503E7 (Murata)

OUTLINE DRAWING SZIP21-P-0.89

Unit: mm







Weight: 1.00 g (Typ.)